



Product Change Notification: CENO-10JZGR405

Date:

15-Jun-2026

Product Category:

Linear Op Amps, Linear Regulators

Notification Subject:

CCB 8337 Final Notice: Qualification of palladium coated copper with gold flash (CuPdAu) as a new bond wire material for MCP1799T-5002H/TT, MCP1799T-3302H/TT, MCP6476UT-E/OT, MCP6006RT-E/OT, MCP6006T-E/OT, MCP6476T-E/OT, MCP6476RT-E/OT, MCP6006UT-E/OT, MCP6486RT-E/OT, MCP6486T-E/OT, MCP6496RT-E/OT, MCP6496UT-E/OT, MCP6496T-E/OT and MCP6486UT-E/OT catalog part numbers (CPN) available in 3L and 5L SOT-23 (1.3mm) packages at MTAI assembly site

Affected CPNs:

[CENO-10JZGR405_Affected_CPN_06152026.pdf](#)

[CENO-10JZGR405_Affected_CPN_06152026.csv](#)

PCN Status: Final Notification

PCN Type: Manufacturing Change

Microchip Parts Affected: Please open one of the files found in the Affected CPNs section.

Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change: Qualification of palladium coated copper with gold flash (CuPdAu) as a new bond wire material for MCP1799T-5002H/TT, MCP1799T-3302H/TT, MCP6476UT-E/OT, MCP6006RT-E/OT, MCP6006T-E/OT, MCP6476T-E/OT, MCP6476RT-E/OT, MCP6006UT-E/OT, MCP6486RT-E/OT, MCP6486T-E/OT, MCP6496RT-E/OT, MCP6496UT-E/OT, MCP6496T-E/OT and MCP6486UT-E/OT catalog part numbers (CPN) available in 3L and 5L SOT-23 (1.3mm) packages at MTAI assembly site

Pre and Post Summary Changes:

	Pre Change	Post Change	Change (Yes/No)

Assembly Site	Microchip Technology Thailand (HQ) (MTAI)	Microchip Technology Thailand (HQ) (MTAI)	No
Wire Material	Au	CuPdAu	Yes
Die Attach Material	84-3J (PFAS-free)	84-3J (PFAS-free)	No
Molding Compound Material	G600V	G600V	No
Lead-Frame Material	A194	A194	No

Impacts to Datasheet: None

Change Impact: None

Reason for Change: To improve productivity by qualifying palladium coated copper with gold flash (CuPdAu) as a new bond wire material.

Change Implementation Status: In Progress

Estimated First Ship Date: 14 September 2026 (date code: 2638)

Note Below EFSD: Note: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

Timetable Summary:

	June 2026					>	September 2026				
Work Week	23	24	25	26	27		36	37	38	39	40
Qual Report Availability			x								
Final PCN Issue Date			x								
Estimated Implementation Date									x		

Method to Identify Change: Traceability Code

Qualification Report: Please open the attachments included with this PCN labeled as PCN_#_Qual_Report.

Revision History:

June 15, 2026: Issued final notification.

Note: The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable product.

Attachments:

PCN_CEN0-10JZGR405 Qual Report.pdf

Please contact your local [Microchip sales office](#) with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to receive Microchip PCNs via email please register for our PCN email service at our [PCN home page](#) select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the [PCN FAQ](#) section.

If you wish to change your PCN profile, including opt out, please go to the [PCN home page](#) select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

Affected Catalog Part Numbers (CPN):

MCP1799T-5002H/TT

MCP1799T-3302H/TT

MCP6476UT-E/OT

MCP6006RT-E/OT

MCP6006T-E/OT

MCP6476T-E/OT

MCP6476RT-E/OT

MCP6006UT-E/OT

MCP6486RT-E/OT

MCP6486T-E/OT

MCP6496RT-E/OT

MCP6496UT-E/OT

MCP6496T-E/OT

MCP6486UT-E/OT



QUALIFICATION REPORT SUMMARY
RELIABILITY LABORATORY

PCN #: CENO-10JZGR405

Date:
January 14, 2025

Qualification of palladium coated copper with gold flash (CuPdAu) as a new bond wire material for MCP1799T-5002H/TT, MCP1799T-3302H/TT, MCP6476UT-E/OT, MCP6006RT-E/OT, MCP6006T-E/OT, MCP6476T-E/OT, MCP6476RT-E/OT, MCP6006UT-E/OT, MCP6486RT-E/OT, MCP6486T-E/OT, MCP6496RT-E/OT, MCP6496UT-E/OT, MCP6496T-E/OT and MCP6486UT-E/OT catalog part numbers (CPN) available in 3L and 5L SOT-23 (1.3mm) packages at MTAI assembly site.

This is a qualification by similarity (QBS).



MICROCHIP PACKAGE QUALIFICATION REPORT

Purpose Qualification of palladium coated copper with gold flash (CuPdAu) as a new bond wire material for MCP1799T-5002H/TT, MCP1799T-3302H/TT, MCP6476UT-E/OT, MCP6006RT-E/OT, MCP6006T-E/OT, MCP6476T-E/OT, MCP6476RT-E/OT, MCP6006UT-E/OT, MCP6486RT-E/OT, MCP6486T-E/OT, MCP6496RT-E/OT, MCP6496UT-E/OT, MCP6496T-E/OT and MCP6486UT-E/OT catalog part numbers (CPN) available in 3L and 5L SOT-23 (1.3mm) packages at MTAI assembly site. This is a qualification by similarity (QBS).

CCB No. 7276 (Qual Date: January 14, 2025) and 8337

CN E000252896

QUAL ID R2401511 Rev. A

MP CODE DFBE1YC8XAA0

Part No. MCP4706A0T-E/CH

Bonding No. BD-002754 Rev. 01

Package

Type 6L SOT-23

Lead Frame

Paddle size 72 x 41 mils

Material A194

Surface Ag single ring Plated

Process Stamped

Lead Lock No

Part Number 10100607

Treatment BOT

Material

Epoxy 84-3J

Wire CuPdAu

Mold Compound G600V

Plating Composition Matte Sn



MICROCHIP

PACKAGE QUALIFICATION REPORT

Manufacturing Information

Assembly Lot No.	Wafer Lot No.	Date Code
MTAI253301572.000	TMPE224408368.430	2446DGP
MTAI253400843.000	TMPE224408368.430	2447ES7
MTAI253400897.000	TMPE224408368.430	2447EUC

Result

☒

Pass

☐

Fail

☐

6L SOT-23 assembled by MTAI pass reliability test per QCI-39000. This package was qualified the Moisture/Reflow Sensitivity Classification Level 1 at 260°C reflow temperature per IPC/JEDEC J-STD-020E standard.

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
Precondition Prior Perform Reliability Tests (At MSL Level 1)	Electrical Test: +25°C and 125°C System: J750_MSO Bake 150°C, 24 hrs. System: CHINEE 85°C/85%RH Moisture Soak 168 hrs. System: TABAI ESPEC Model PR-3SPH 3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243	JESD22-A113 JIP/ IPC/JEDEC J-STD-020E	693(0)	0/693	Pass	Good Devices
	Electrical Test: +25°C and 125°C System: J750_MSO		693(0)	0/693	Pass	

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
Temp Cycle	Stress Condition: -65°C to +150°C, 500 Cycles System: TABAI ESPEC TSA-70H	JESD22-A104		0/231		Parts had been pre-conditioned at 260°C
	Electrical Test: + 125°C System: J750_MSO		231(0)	0/231	Pass	77 units / lot
	Bond Strength: Wire Pull (>3.00 grams)		15(0)	0/15	Pass	
UNBIASED-HAST	Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X	JESD22-A118		0/231		Parts had been pre-conditioned at 260°C
	Electrical Test: +25°C System: J750_MSO		231(0)	0/231	Pass	77 units / lot
HAST	Stress Condition: +130°C/85%RH, 96 hrs. Bias Volt : Vdd= 5.0 Volts System: HAST 6000X	JESD22-A110		0/231		Parts had been pre-conditioned at 260°C
	Electrical Test: +25°C and 125°C System: J750_MSO		231(0)	0/231	Pass	77 units / lot

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
High Temperature Storage Life	Stress Condition: Bake 175°C, 504 hrs. System: TPS Bake Oven	JESD22- A103		0/135		45 units / lot
	Electrical Test: +25°C and 125°C System: J750_MSO		135(0)	0/135	Pass	
Bond Strength Data Assembly	Wire Pull (>3.00 grams)	Mil. Std. 883-2011	30(0) Wires	0/30	Pass	
	Bond Shear (>15.00 grams)	CDF-AEC- Q100-001	30(0) bonds	0/30	Pass	